

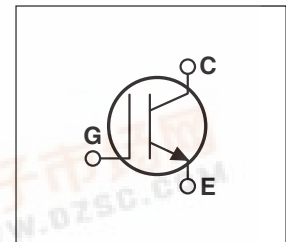
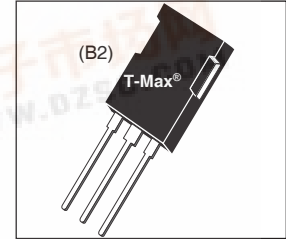


1200V
APT50GN120B2
APT50GN120B2G*

*G Denotes RoHS Compliant, Pb Free Terminal Finish.

Utilizing the latest Non-Punch Through (NPT) Field Stop technology, these IGBT's have a very short, low amplitude tail current and low Eoff. The Trench Gate design results in superior $V_{CE(on)}$ performance. Easy paralleling results from very tight parameter distribution and slightly positive $V_{CE(on)}$ temperature coefficient. Built-in gate resistance ensures ultra-reliable operation. Low gate charge simplifies gate drive design and minimizes losses.

- **1200V NPT Field Stop**
- **Trench Gate: Low $V_{CE(on)}$**
- **Easy Paralleling**
- **10 μ s Short Circuit Capability**
- **Intergrated Gate Resistor: Low EMI, High Reliability**



Applications: Welding, Inductive Heating, Solar Inverters, SMPS, Motor drives, UPS

MAXIMUM RATINGS

All Ratings: $T_C = 25^\circ\text{C}$ unless otherwise specified.

Symbol	Parameter	APT50GN120B2(G)	UNIT
V_{CES}	Collector-Emitter Voltage	1200	Volts
V_{GE}	Gate-Emitter Voltage	± 30	
I_{C1}	Continuous Collector Current ^⑧ @ $T_C = 25^\circ\text{C}$	134	Amps
I_{C2}	Continuous Collector Current @ $T_C = 110^\circ\text{C}$	66	
I_{CM}	Pulsed Collector Current ^① @ $T_C = 150^\circ\text{C}$	150	
SSOA	Switching Safe Operating Area @ $T_J = 150^\circ\text{C}$	150A @ 1200V	
P_D	Total Power Dissipation	543	Watts
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to 150	$^\circ\text{C}$
T_L	Max. Lead Temp. for Soldering: 0.063" from Case for 10 Sec.	300	

STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	Units
$V_{(BR)CES}$	Collector-Emitter Breakdown Voltage ($V_{GE} = 0V, I_C = 400\mu\text{A}$)	1200			Volts
$V_{GE(TH)}$	Gate Threshold Voltage ($V_{CE} = V_{GE}, I_C = 2\text{mA}, T_J = 25^\circ\text{C}$)	5	5.8	6.5	
$V_{CE(ON)}$	Collector-Emitter On Voltage ($V_{GE} = 15V, I_C = 50A, T_J = 25^\circ\text{C}$)	1.4	1.7	2.1	
	Collector-Emitter On Voltage ($V_{GE} = 15V, I_C = 50A, T_J = 125^\circ\text{C}$)		1.9		
I_{CES}	Collector Cut-off Current ($V_{CE} = 1200V, V_{GE} = 0V, T_J = 25^\circ\text{C}$) ^②			100	μA
	Collector Cut-off Current ($V_{CE} = 1200V, V_{GE} = 0V, T_J = 125^\circ\text{C}$) ^②			TBD	
I_{GES}	Gate-Emitter Leakage Current ($V_{GE} = \pm 20V$)			600	nA
R_{GINT}	Intergrated Gate Resistor		4		Ω

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

DYNAMIC CHARACTERISTICS

APT50GN120B2(G)

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT	
C _{ies}	Input Capacitance	Capacitance V _{GE} = 0V, V _{CE} = 25V f = 1 MHz		3600		pF	
C _{oes}	Output Capacitance			210			
C _{res}	Reverse Transfer Capacitance			170			
V _{GEP}	Gate-to-Emitter Plateau Voltage	Gate Charge		9.5		V	
Q _g	Total Gate Charge ^③	V _{GE} = 15V		315		nC	
Q _{ge}	Gate-Emitter Charge	V _{CE} = 600V		20			
Q _{gc}	Gate-Collector ("Miller") Charge	I _C = 50A		190			
SSOA	Switching Safe Operating Area	T _J = 150°C, R _G = 2.2Ω ^⑦ , V _{GE} = 15V, L = 100μH, V _{CE} = 1200V	150			A	
SCSOA	Short Circuit Safe Operating Area	V _{CC} = 960V, V _{GE} = 15V, T _J = 125°C, R _G = 2.2Ω ^⑦	10			μs	
t _{d(on)}	Turn-on Delay Time	Inductive Switching (25°C) V _{CC} = 800V V _{GE} = 15V I _C = 50A R _G = 2.2Ω ^⑦ T _J = +25°C		28		ns	
t _r	Current Rise Time			27			
t _{d(off)}	Turn-off Delay Time			320			
t _f	Current Fall Time			115			
E _{on1}	Turn-on Switching Energy ^④				TBD		μJ
E _{on2}	Turn-on Switching Energy (Diode) ^⑤				3900		
E _{off}	Turn-off Switching Energy ^⑥				4495		
t _{d(on)}	Turn-on Delay Time		Inductive Switching (125°C) V _{CC} = 800V V _{GE} = 15V I _C = 50A R _G = 2.2Ω ^⑦ T _J = +125°C		28		ns
t _r	Current Rise Time			27			
t _{d(off)}	Turn-off Delay Time			395			
t _f	Current Fall Time			205			
E _{on1}	Turn-on Switching Energy ^④				TBD		μJ
E _{on2}	Turn-on Switching Energy (Diode) ^⑤				5660		
E _{off}	Turn-off Switching Energy ^⑥				6795		

THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
R _{θJC}	Junction to Case (IGBT)			.23	°C/W
R _{θJC}	Junction to Case (DIODE)			N/A	
W _T	Package Weight		5.9		gm

- ① Repetitive Rating: Pulse width limited by maximum junction temperature.
- ② For Combi devices, I_{ces} includes both IGBT and FRED leakages
- ③ See MIL-STD-750 Method 3471.
- ④ E_{on1} is the clamped inductive turn-on-energy of the IGBT only, without the effect of a commutating diode reverse recovery current adding to the IGBT turn-on loss. (See Figure 24.)
- ⑤ E_{on2} is the clamped inductive turn-on energy that includes a commutating diode reverse recovery current in the IGBT turn-on switching loss. (See Figures 21, 22.)
- ⑥ E_{off} is the clamped inductive turn-off energy measured in accordance with JEDEC standard JESD24-1. (See Figures 21, 23.)
- ⑦ R_G is external gate resistance, not including R_{Gint} nor gate driver impedance.
- ⑧ Continuous current limited by package lead temperature.

APT Reserves the right to change, without notice, the specifications and information contained herein.

TYPICAL PERFORMANCE CURVES

APT50GN120B2(G)

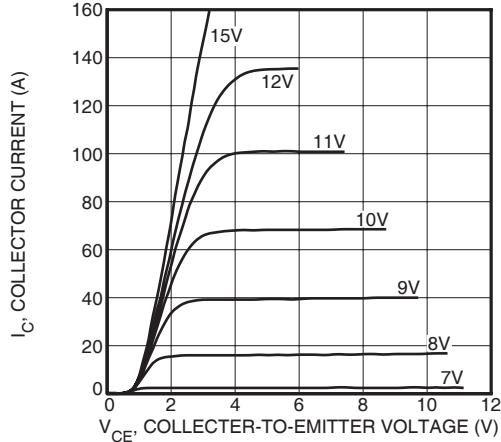


FIGURE 1, Output Characteristics ($T_J = 25^\circ\text{C}$)

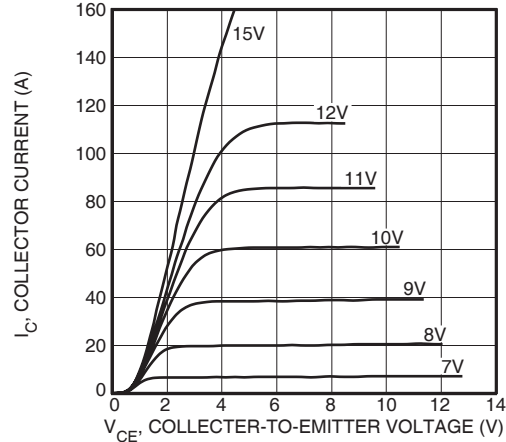


FIGURE 2, Output Characteristics ($T_J = 125^\circ\text{C}$)

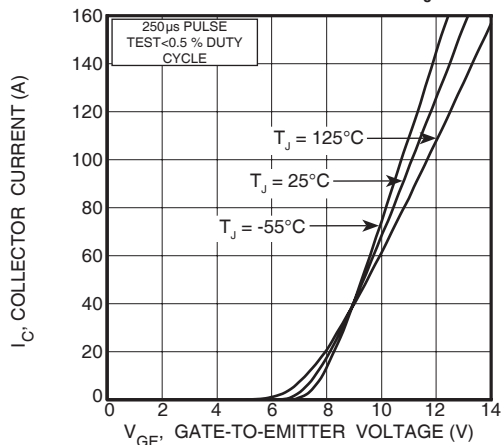


FIGURE 3, Transfer Characteristics

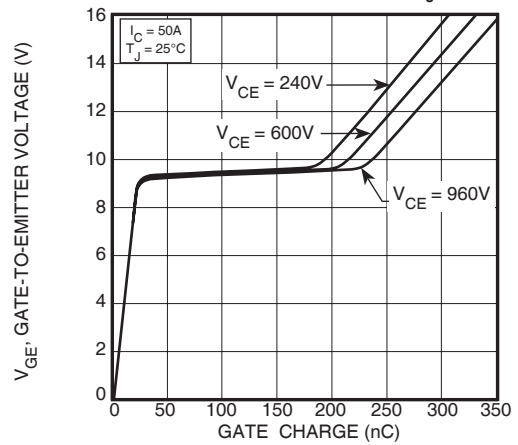


FIGURE 4, Gate Charge

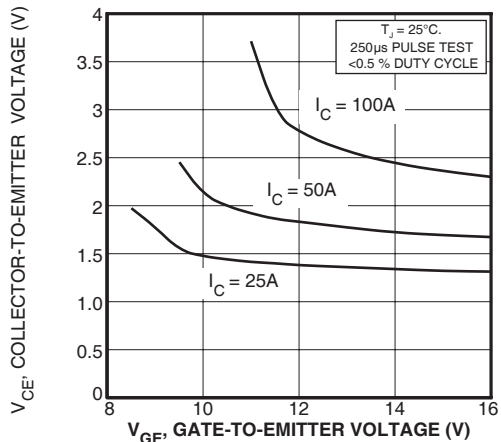


FIGURE 5, On State Voltage vs Gate-to-Emitter Voltage

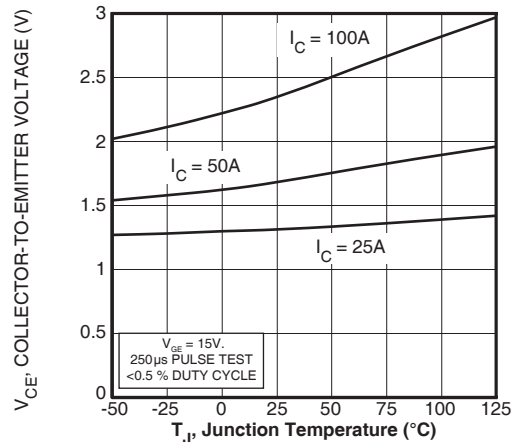


FIGURE 6, On State Voltage vs Junction Temperature

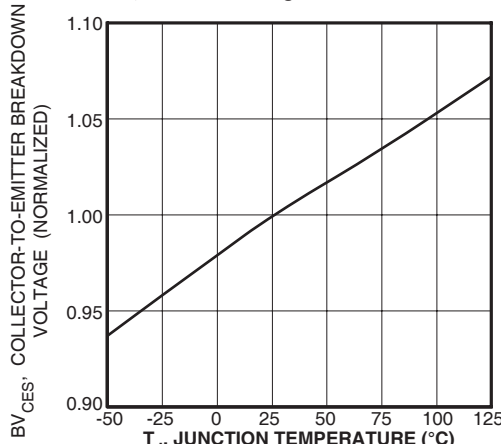


FIGURE 7, Breakdown Voltage vs. Junction Temperature

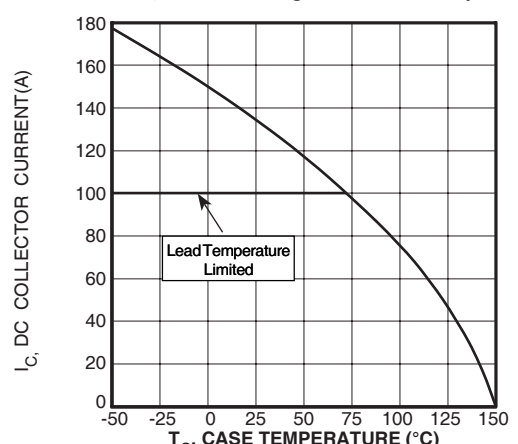


FIGURE 8, DC Collector Current vs Case Temperature

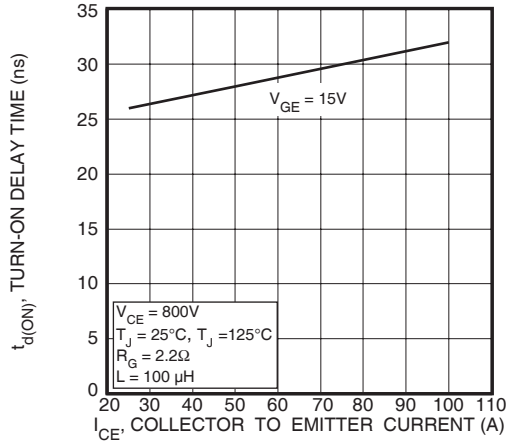


FIGURE 9, Turn-On Delay Time vs Collector Current

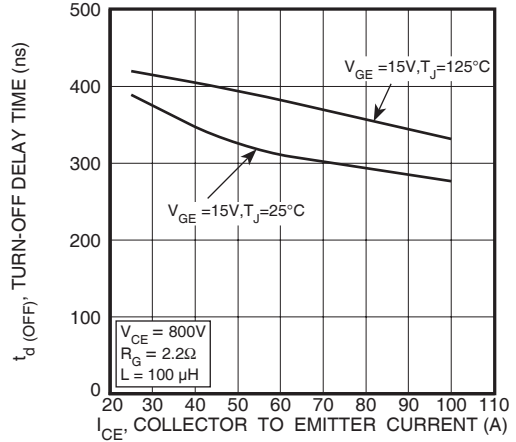


FIGURE 10, Turn-Off Delay Time vs Collector Current

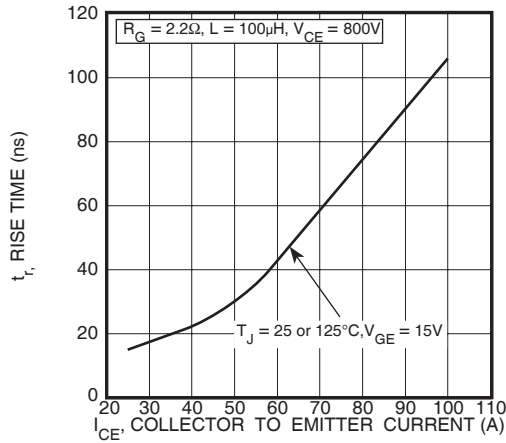


FIGURE 11, Current Rise Time vs Collector Current

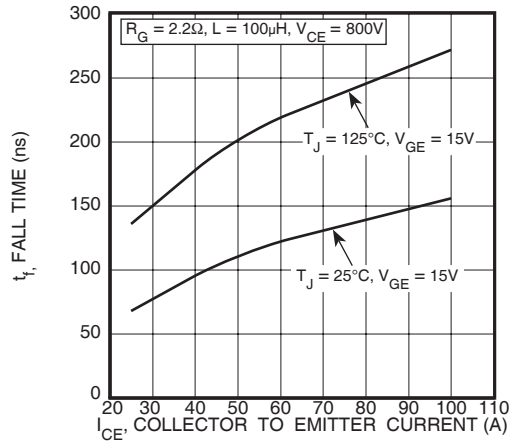


FIGURE 12, Current Fall Time vs Collector Current

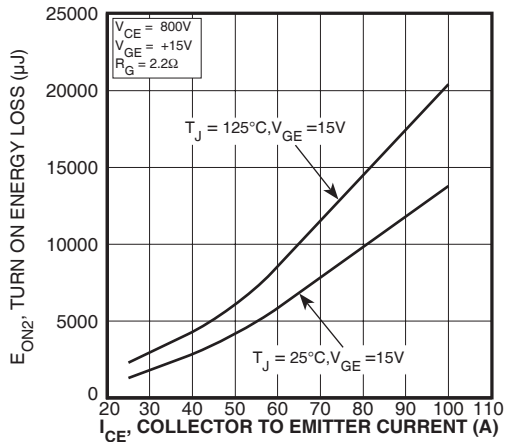


FIGURE 13, Turn-On Energy Loss vs Collector Current

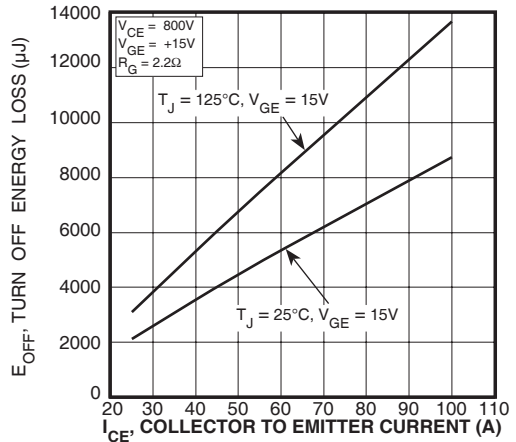


FIGURE 14, Turn Off Energy Loss vs Collector Current

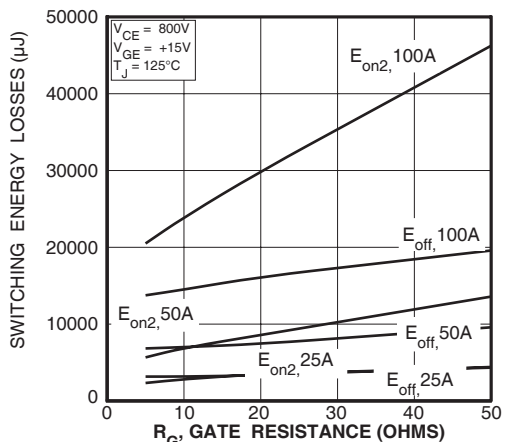


FIGURE 15, Switching Energy Losses vs. Gate Resistance

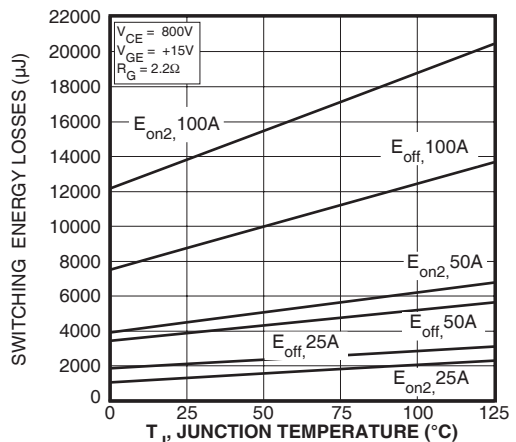


FIGURE 16, Switching Energy Losses vs Junction Temperature

TYPICAL PERFORMANCE CURVES

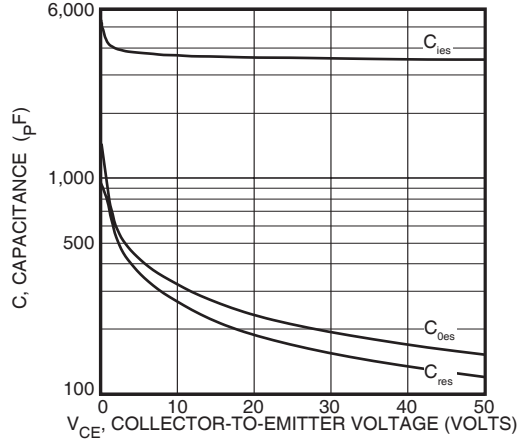


Figure 17, Capacitance vs Collector-To-Emitter Voltage

APT50GN120B2(G)

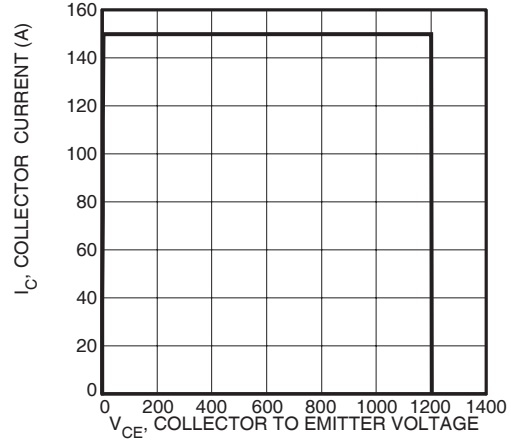


Figure 18, Minimum Switching Safe Operating Area

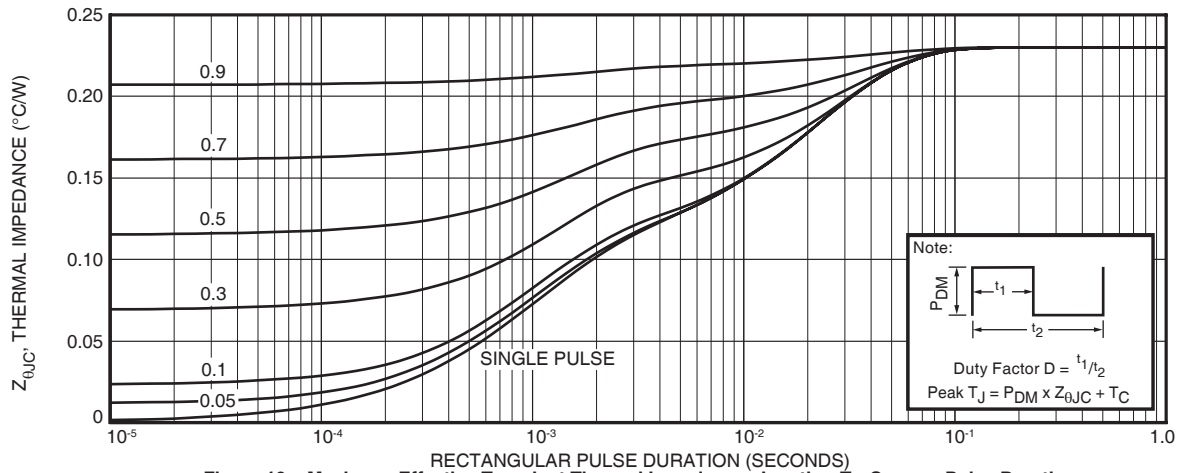


Figure 19a, Maximum Effective Transient Thermal Impedance, Junction-To-Case vs Pulse Duration

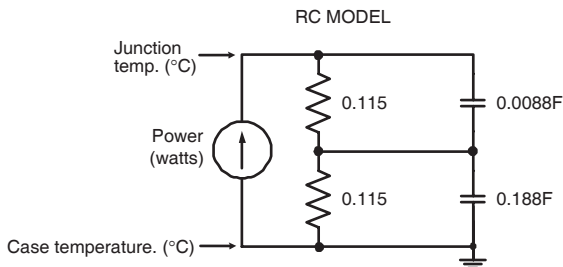


FIGURE 19b, TRANSIENT THERMAL IMPEDANCE MODEL

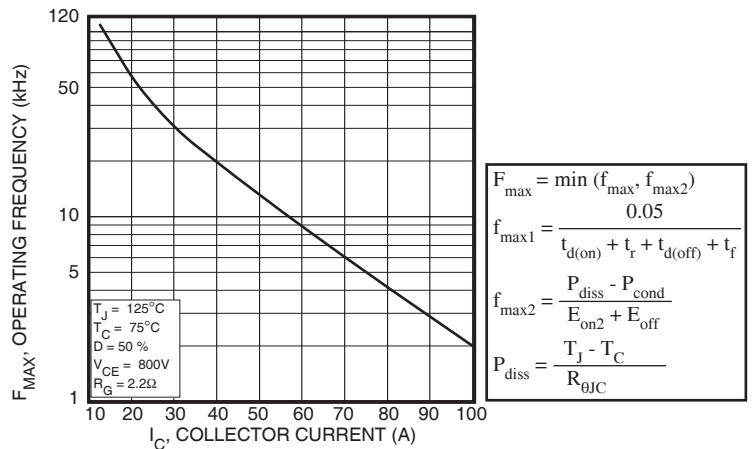


Figure 20, Operating Frequency vs Collector Current

APT50GN120B2(G)

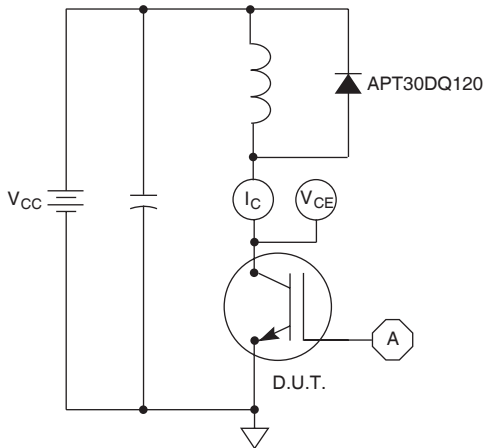


Figure 21, Inductive Switching Test Circuit

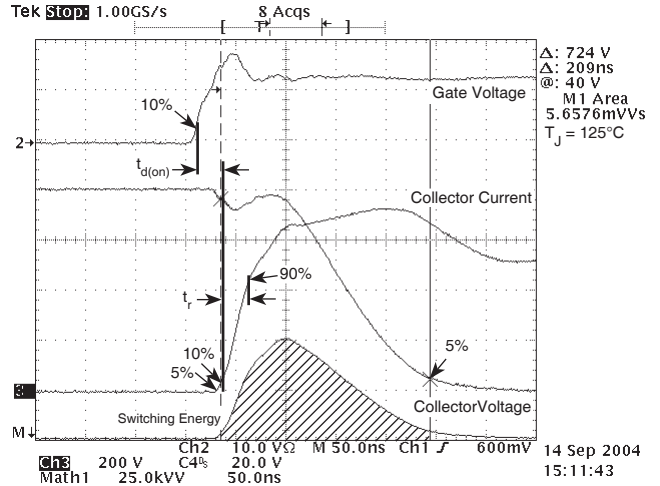


Figure 22, Turn-on Switching Waveforms and Definitions

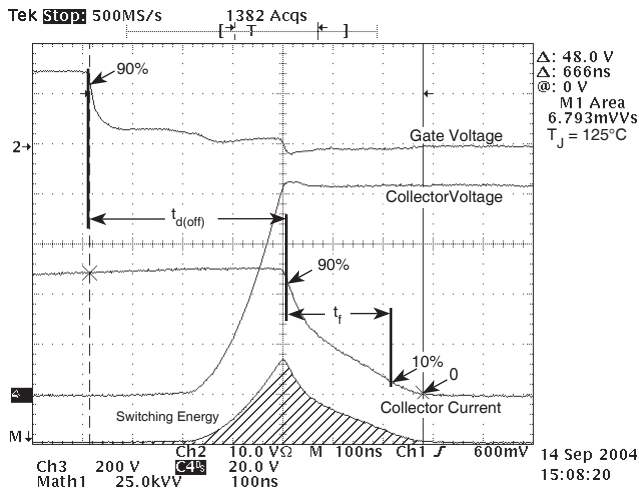


Figure 23, Turn-off Switching Waveforms and Definitions

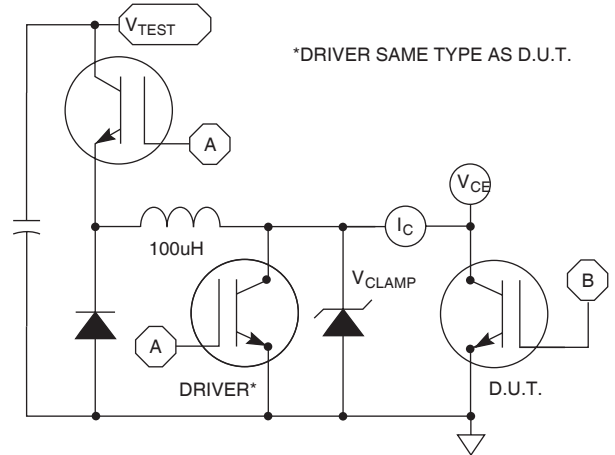
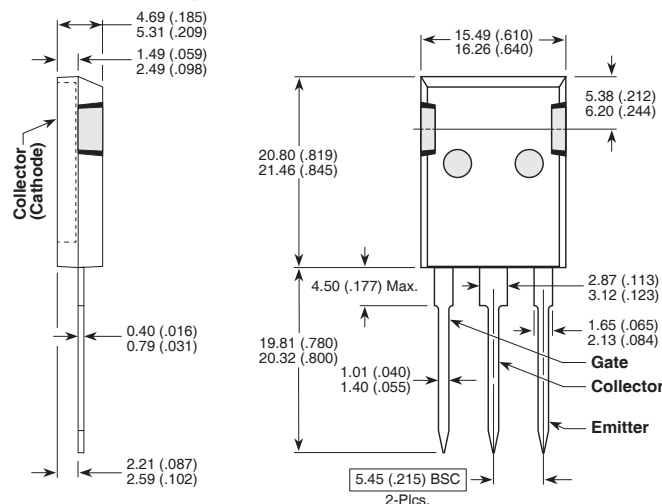


Figure 24, E_{ON1} Test Circuit

T-MAX™ (B2) Package Outline

① SAC: Tin, Silver, Copper



Dimensions in Millimeters and (Inches)